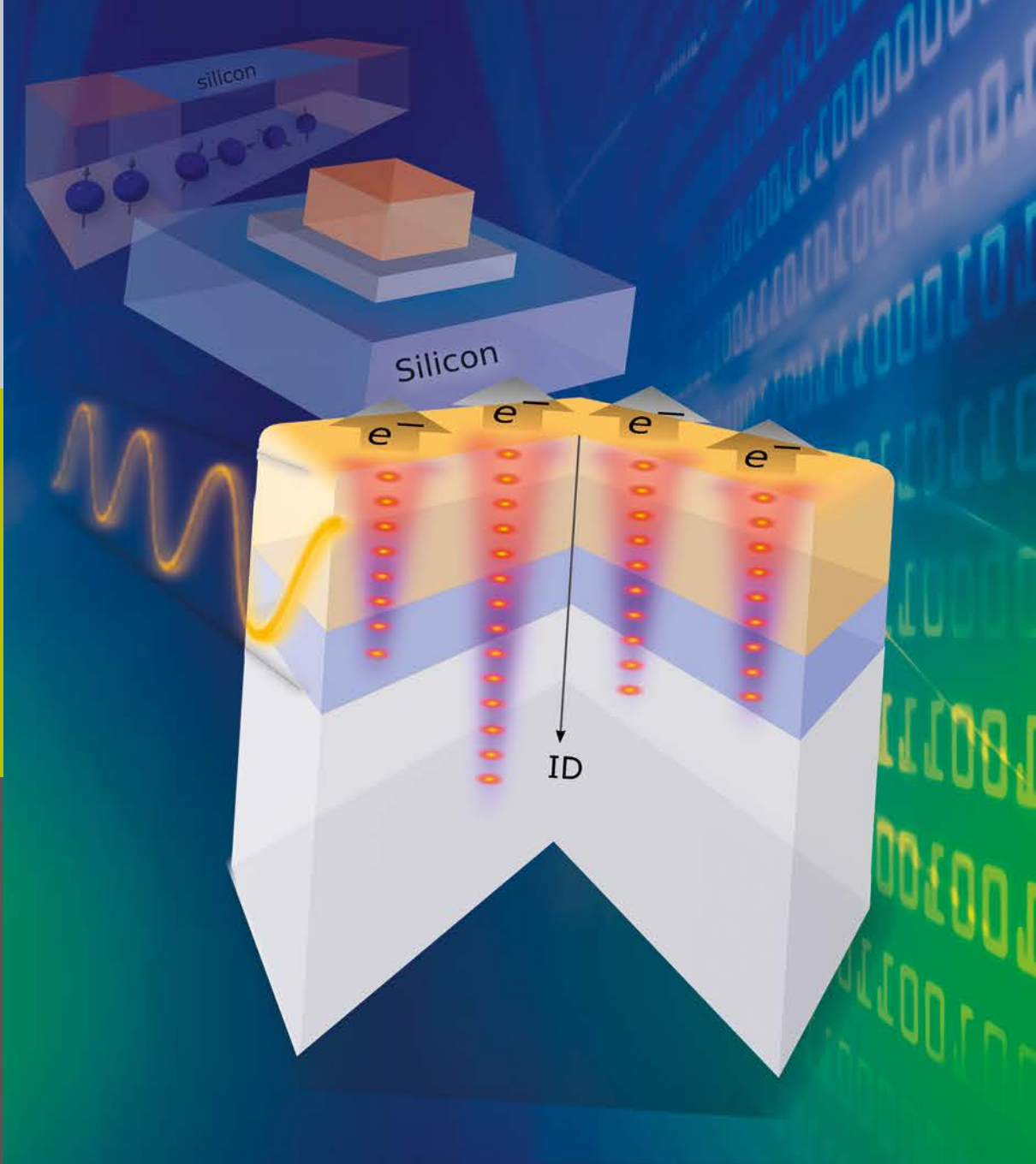




Magnetic Oxide Heterostructures: EuO on Cubic Oxides and on Silicon

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